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Call for papers

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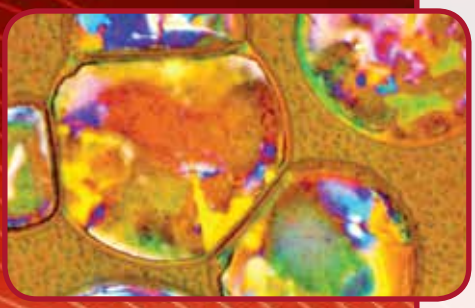

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Manuscript Deadline: *January 1, 2020*

Advanced Characterization of Interfaces and Thin Films

Interfaces play an important role in modifying materials properties--structural, electronic, optical and magnetic, etc. The focus of this topic is the advanced characterization of materials interfaces at atomic and nanoscales in metal, alloys, ceramics, and polymers by various in-situ and ex-situ experimental techniques such as x-ray and neutron diffraction, scanning electron microscopy, transmission electron microscopy, and atomic force microscopy. This topic also involves the understanding of materials interfaces by theoretical modeling approaches that allow the study of these processes on the atomic and molecular level.

Original research papers should be 3,000-6,000 words with up to 8 figures maximum; review papers should be 6,000-10,000 words with up to 15 figures maximum.

Detailed author instructions are available at:
http://www.tms.org/AuthorTools/

Keywords for this topic: **Advanced Materials; Electronic Materials; Energy Conversion and Storage**

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Committee Sponsor(s): **Thin Films and Interfaces**

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